

## FDD6680S

## 30V N-Channel PowerTrench® SyncFET<sup>™</sup>

### **General Description**

The FDD6680S is designed to replace a single MOSFET and Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low  $R_{\rm DS(ON)}$  and low gate charge. The FDD6680S includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology. The performance of the FDD6680S as the low-side switch in a synchronous rectifier is indistinguishable from the performance of the FDD6680A in parallel with a Schottky diode.

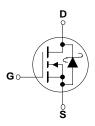
### **Applications**

- DC/DC converter
- Motor Drives

### **Features**

- 55 A, 30 V  $R_{DS(ON)} = 11 \ m\Omega \ @ \ V_{GS} = 10 \ V$   $R_{DS(ON)} = 17 \ m\Omega \ @ \ V_{GS} = 4.5 \ V$
- Includes SyncFET Schottky body diode
- Low gate charge (17nC typical)
- High performance trench technology for extremely low  $R_{\mbox{\scriptsize DS(ON)}}$
- High power and current handling capability

G S TO-252



Absolute Maximum Ratings T<sub>A=25°C</sub> unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		30	V
V <sub>GSS</sub>	Gate-Source Voltage		±20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 3)	55	А
	- Pulsed	(Note 1a)	100	
P <sub>D</sub>	Power Dissipation	(Note 1)	60	W
		(Note 1a)	3.1	
		(Note 1b)	1.3	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C

### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	2.1	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape width	Quantity	
FDD6680S	FDD6680S	13"	16mm	2500 units	

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	ource Avalanche Ratings (Not	e 2)	I	I		I
W <sub>DSS</sub>	Drain-Source Avalanche Energy	Single Pulse, V <sub>DD</sub> = 15 V, I <sub>D</sub> =14A			245	mJ
I <sub>AR</sub>	Drain-Source Avalanche Current				14	Α
Off Char	acteristics	•		•		•
BV <sub>DSS</sub>	Drain–Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 1 \text{ mA}$	30			V
ΔBV <sub>DSS</sub> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 1 mA, Referenced to 25°C		19		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V			500	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V},  V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)	•		•		
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 1 \text{ mA}$	1	2	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 1 mA, Referenced to 25°C		-3.3		mV/°0
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$\begin{aligned} &V_{GS} = 10 \text{ V}, &I_{D} = 12.5 \text{ A} \\ &V_{GS} = 4.5 \text{ V}, &I_{D} = 10 \text{ A} \\ &V_{GS} = 10 \text{ V}, I_{D} = 12.5 \text{A}, T_{J} = 125^{\circ}\text{C} \end{aligned}$		9.5 13.5 17	11 17 23	mΩ
I <sub>D(on)</sub>	On–State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	50			Α
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 12.5 \text{ A}$		27		S
Dvnamic	Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		2010		pF
Coss	Output Capacitance	f = 1.0 MHz		526		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			186		pF
Switchin	ng Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 1 \text{ A},$		10	18	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		10	18	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			34	55	ns
t <sub>f</sub>	Turn-Off Fall Time			14	23	ns
Qg	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 12.5 \text{ A},$		17	24	nC
$Q_{gs}$	Gate-Source Charge	$V_{GS} = 5 V$		6.2		nC
$Q_{gd}$	Gate-Drain Charge			5.5		nC
Drain-Se	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source				4.4	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_S = 4.4 \text{ A}  \text{(Note 2)} \\ V_{GS} = 0 \text{ V},  I_S = 7 \text{ A}  \text{(Note 2)}$		0.49 0.56	0.7	V
t <sub>rr</sub>	Diode Reverse Recovery Time	$I_F = 12.5A,$		20		nS
Qrr	Diode Reverse Recovery Charge	$d_{iF}/d_t = 300 \text{ A/}\mu\text{s} \qquad \text{(Note 3)}$		19.7		nC

### **Electrical Characteristics**

T<sub>A</sub> = 25°C unless otherwise noted

#### Notes

1.  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



a)  $R_{\theta JA} = 40$  °C/W when mounted on a  $1 \text{in}^2$  pad of 2 oz copper



b)  $R_{\theta JA} = 96$ °C/W when mounted on a minimum pad.

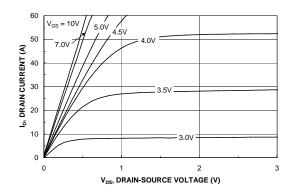
Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

3. Maximum current is calculated as:  $\sqrt{\frac{P_D}{R_{DS(ON)}}}$ 

where  $P_D$  is maximum power dissipation at  $T_C = 25^{\circ}C$  and  $R_{DS(on)}$  is at  $T_{J(max)}$  and  $V_{GS} = 10V$ . Package current limitation is 21A

### **Typical Characteristics**



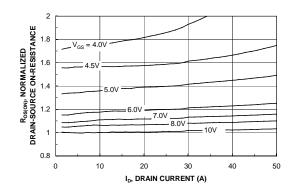
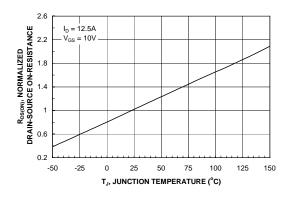


Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.



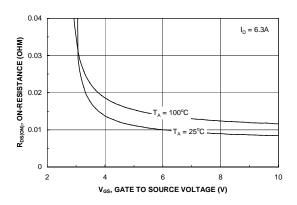
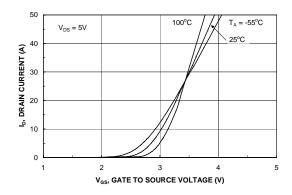


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



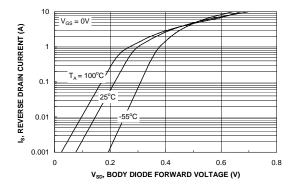
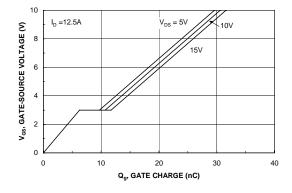


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

### **Typical Characteristics** (continued)



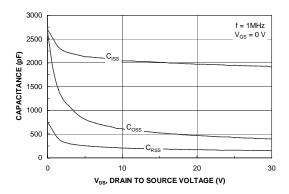
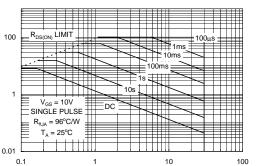


Figure 7. Gate Charge Characteristics.



V<sub>DS</sub>, DRAIN-SOURCE VOLTAGE (V)

ID, DRAIN CURRENT (A)

Figure 8. Capacitance Characteristics.

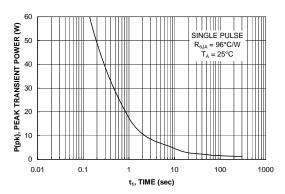


Figure 9. Maximum Safe Operating Area.



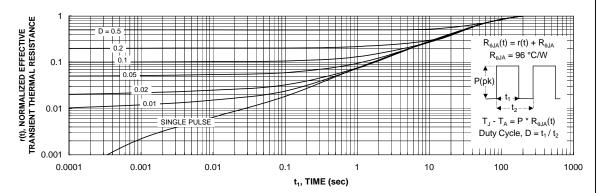


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

### **Typical Characteristics** (continued)

# SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDD6680S.

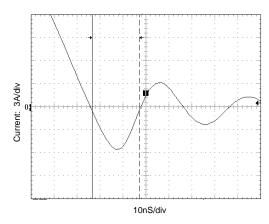


Figure 12. FDD6680S SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDD6680).

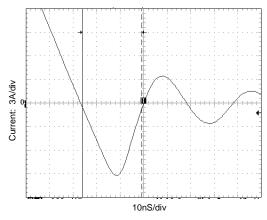


Figure 13. Non-SyncFET (FDS6680) body diode reverse recovery characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

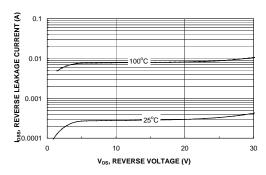


Figure 14. SyncFET body diode reverse leakage versus drain-source voltage and temperature.

### **TRADEMARKS**

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

 $ACEx^{TM}$ FASTr™ PowerTrench® SyncFET™ Bottomless™ QFET™ TinyLogic™ GlobalOptoisolator™ QSTM UHC™ CoolFET™ GTO™ **VCX**<sup>TM</sup>  $CROSSVOLT^{TM}$ QT Optoelectronics™ HiSeC™

DOME™ ISOPLANAR™ Quiet Series™

#### **DISCLAIMER**

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

#### LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.
- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

#### PRODUCT STATUS DEFINITIONS

#### **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.